

Notice of References Cited	Application/Control No. 10/542,837	Applicant(s)/Patent Under Reexamination VAN LEEST ET AL.	
	Examiner NANCY BITAR	Art Unit 2624	Page 1 of 1

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*	B	US-7,706,569	04-2010	Iwamura, Keichi	382/100
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NON-PATENT DOCUMENTS

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